

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10662470	EKBERG, JAN-ERIK
	<b>Examiner</b>	<b>Art Unit</b>
	Ho, Huy C	2617

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
709	228	5/25/07	HH
370	338	5/25/07	HH

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST search in USPAT, US PGPUB, USOCR, JPO, DERWENT, IBM(See attached search strategy)	1/18/07	HH
Search update	5/25/07	HH
Search update	11/25/2007	HH

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>